

Search Notes

Application/Control No.

10/721,380

Examiner

German Viana Di Prisco

Applicant(s)/Patent under
Reexamination

KIM, TAE-KON

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
370	908	1/11/2008	GV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT,EPO,JPO and IBM_TDB (see attached search strategy)	1/11/2008	GV
inventor name and Assignee search in PALM ExPO and EAST	1/11/2008	GV
IEEE Xplore(http://ieeexplore.ieee.org/Xplora/DynWeb.jsp)	1/11/2008	GV
Korea Institute of Patent Information http://eng.kipris.or.kr/	1/11/2008	GV
Consulted with Rafael Perez-Gutierrez Ken Vanderpuye and Duc Nguyen	1/11/2008	GV
EPO Database(http://eo.espacenet.com)	1/11/2008	GV
(point adj coordinator or pc) and (cfp or (contention adj free adj period)) and queue	1/11/2008	GV